Notice of References Cited Application/Control No. O9/665,715 Examiner Kim T. Huynh Applicant(s)/Patent Under Reexamination SCHEEL ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2003/0172201	09-2003	HATAE et al.	710/8
	В	US-			
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	Е	US-		-	
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FOREIGN PATENT DOCUMENTS

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